



OPTO-ÉLECTRONIQUE

Travaux Pratiques

Semestre 5

Documentations techniques

- SFH206K
- LED Rouge
- TL081

Les documentations techniques sont disponibles sur le site des constructeurs.

Radial Sidelooker

SFH 206 K

Silicon PIN Photodiode



Applications

- Access Control & Security
- Appliances & Tools

Features

- Package: clear epoxy
- ESD: 2 kV acc. to ANSI/ESDA/JEDEC JS-001 (HBM, Class 2)
- Especially suitable for applications from 400 nm to 1100 nm
- Short switching time (typ. 20 ns)
- 5 mm LED plastic package
- Also available on tape and reel

Maximum Ratings

 $T_A = 25\text{ °C}$

Parameter	Symbol	Values	
Operating Temperature	T_{op}	min.	-40 °C
		max.	100 °C
Storage temperature	T_{stg}	min.	-40 °C
		max.	100 °C
Reverse voltage	V_R	max.	32 V
Total power dissipation	P_{tot}	max.	150 mW
ESD withstand voltage acc. to ANSI/ESDA/JEDEC JS-001 (HBM, Class 2)	V_{ESD}	max.	2 kV

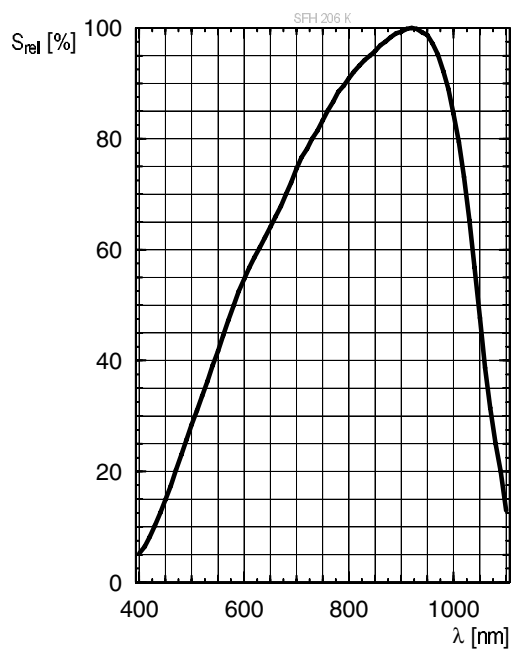
Characteristics

$T_A = 25\text{ °C}$

Parameter	Symbol		Values
Spectral sensitivity $V_R = 5\text{ V}$; Std. Light A; $T = 2856\text{ K}$	S	min. typ.	50 nA/lx 80 nA/lx
Wavelength of max sensitivity	$\lambda_{S\text{ max}}$	typ.	920 nm
Spectral range of sensitivity	$\lambda_{10\%}$	typ.	420 ... 1120 nm
Radiant sensitive area	A	typ.	7.02 mm ²
Dimensions of active chip area	L x W	typ.	2.65 x 2.65 mm x mm
Half angle	φ	typ.	60 °
Dark current $V_R = 10\text{ V}$	I_R	typ. max.	2 nA 30 nA
Spectral sensitivity of the chip $\lambda = 850\text{ nm}$	S_λ	typ.	0.62 A / W
Quantum yield of the chip $\lambda = 850\text{ nm}$	η	typ.	0.90 Electrons / Photon
Open-circuit voltage $E_v = 1000\text{ lx}$; Std. Light A; $V_R = 0\text{ V}$	V_O	min. typ.	310 mV 365 mV
Short-circuit current $E_v = 1000\text{ lx}$; Std. Light A; $V_R = 0\text{ V}$	I_{SC}	typ.	80 μ A
Rise time $V_R = 5\text{ V}$; $R_L = 50\text{ }\Omega$; $\lambda = 850\text{ nm}$; $I_p = 800\text{ }\mu$ A	t_r	typ.	0.02 μ s
Fall time $V_R = 5\text{ V}$; $R_L = 50\text{ }\Omega$; $\lambda = 850\text{ nm}$; $I_p = 800\text{ }\mu$ A	t_f	typ.	0.02 μ s
Forward voltage $I_F = 100\text{ mA}$; $E = 0$	V_F	typ.	1.3 V
Capacitance $V_R = 0\text{ V}$; $f = 1\text{ MHz}$; $E = 0$	C_0	typ.	72 pF
Temperature coefficient of voltage	TC_V	typ.	-2.6 mV / K
Temperature coefficient of short-circuit current Std. Light A	TC_I	typ.	0.18 % / K
Noise equivalent power $V_R = 10\text{ V}$; $\lambda = 850\text{ nm}$	NEP	typ.	0.041 pW / Hz ^{1/2}
Detection limit $V_R = 10\text{ V}$; $\lambda = 850\text{ nm}$	D^*	typ.	6.5e12 cm x Hz ^{1/2} / W

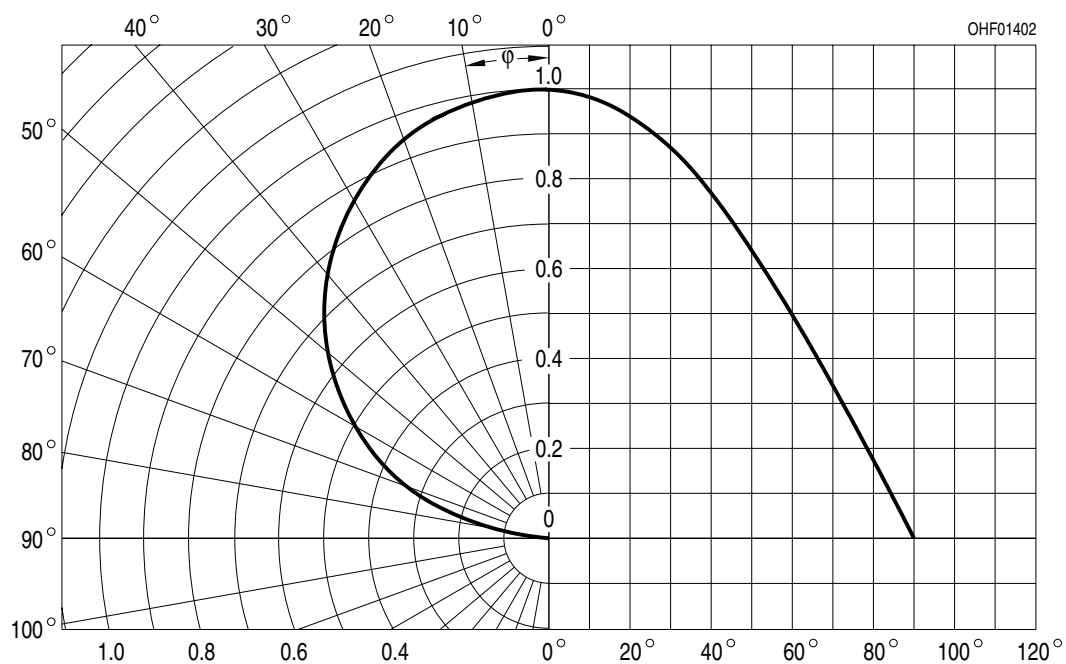
Relative Spectral Sensitivity ²⁾, ³⁾

$$S_{\text{rel}} = f(\lambda)$$



Directional Characteristics ²⁾, ³⁾

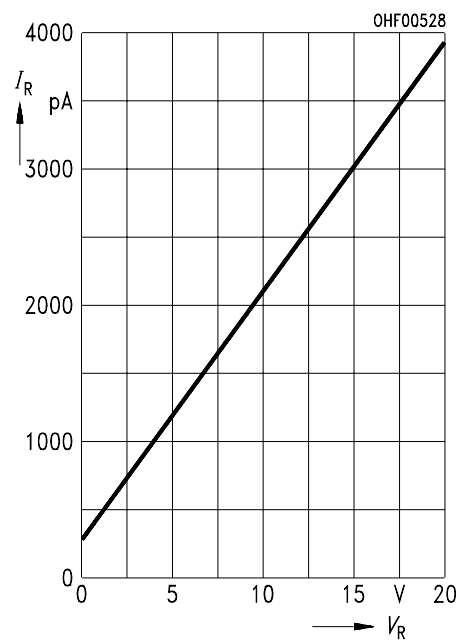
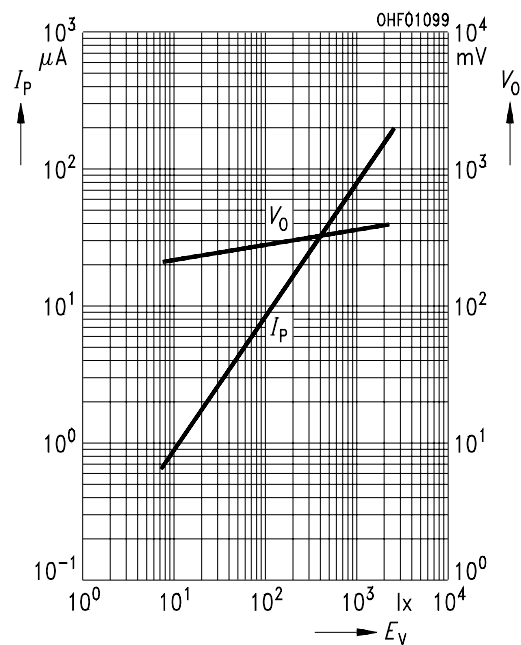
$$S_{\text{rel}} = f(\varphi)$$



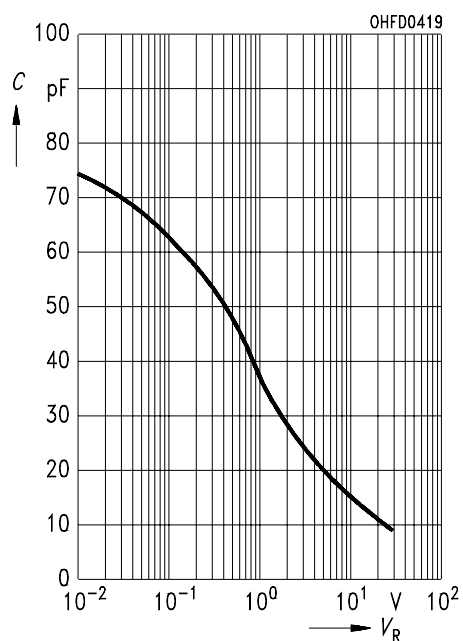
Photocurrent/Open-Circuit Voltage 2), 3) **Dark Current** 2), 3)

$$I_P (V_R = 5 \text{ V}) / V_O = f(E_V)$$

$$I_R = f(V_R); E = 0$$

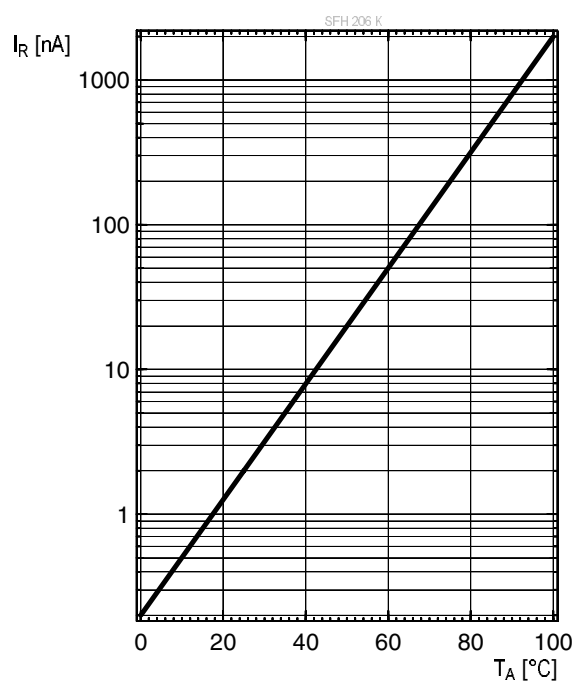
**Capacitance** 2), 3)

$$C = f(V_R); f = 1 \text{ MHz}; E = 0; T_A = 25^\circ\text{C}$$



Dark Current ²⁾

$$I_R = f(T_A); E = 0; V_R = 10 \text{ V}$$



Part Number: L-1503ID

High Efficiency Red

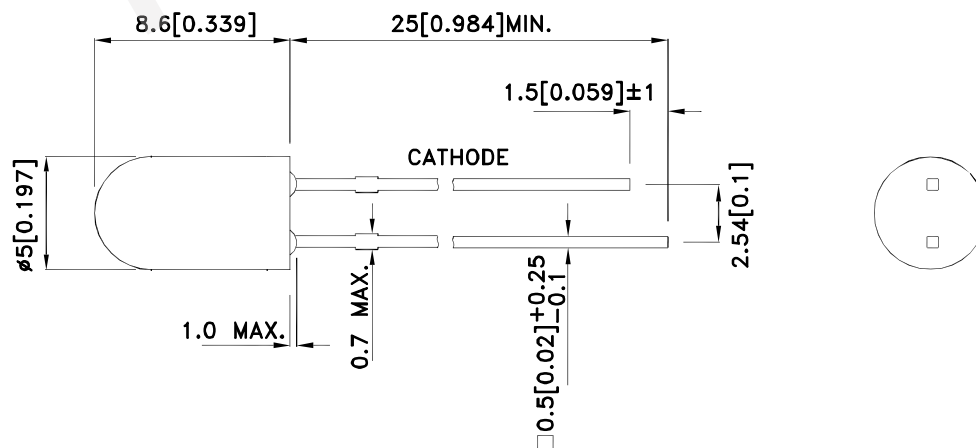
Features

- Low power consumption.
- Versatile mounting on P.C. board or panel.
- T-1 3/4 diameter flangeless package.
- Reliable and rugged.
- RoHS compliant.

Description

The High Efficiency Red source color devices are made with Gallium Arsenide Phosphide on Gallium Phosphide Orange Light Emitting Diode.

Package Dimensions



Notes:

1. All dimensions are in millimeters (inches).
2. Tolerance is $\pm 0.25(0.01)$ unless otherwise noted.
3. Lead spacing is measured where the leads emerge from the package.
4. The specifications, characteristics and technical data described in the datasheet are subject to change without prior notice.



Selection Guide

Part No.	Dice	Lens Type	Iv (mcd) [2] @ 10mA		Viewing Angle [1]
			Min.	Typ.	2θ1/2
L-1503ID	High Efficiency Red (GaAsP/GaP)	Red Diffused	25	50	60°
			*12	*40	

Notes:

1. $\theta_{1/2}$ is the angle from optical centerline where the luminous intensity is 1/2 of the optical peak value.
2. Luminous intensity/ luminous Flux: +/-15%.
- * Luminous intensity value is traceable to the CIE127-2007 compliant national standards.

Electrical / Optical Characteristics at TA=25°C

Symbol	Parameter	Device	Typ.	Max.	Units	Test Conditions
λ_{peak}	Peak Wavelength	High Efficiency Red	627		nm	I _F =20mA
λ_D [1]	Dominant Wavelength	High Efficiency Red	617		nm	I _F =20mA
$\Delta\lambda_{1/2}$	Spectral Line Half-width	High Efficiency Red	45		nm	I _F =20mA
C	Capacitance	High Efficiency Red	15		pF	V _F =0V; f=1MHz
V _F [2]	Forward Voltage	High Efficiency Red	2	2.5	V	I _F =20mA
I _R	Reverse Current	High Efficiency Red		10	uA	V _R = 5V

Notes:

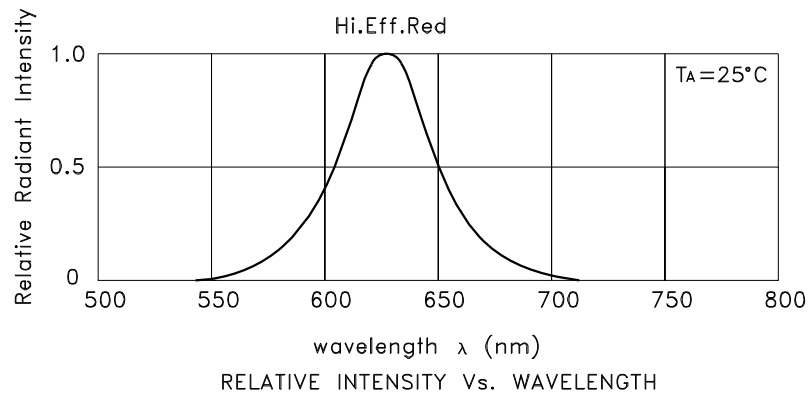
1. Wavelength: +/-1nm.
2. Forward Voltage: +/-0.1V.
3. Wavelength value is traceable to the CIE127-2007 compliant national standards.

Absolute Maximum Ratings at TA=25°C

Parameter	High Efficiency Red	Units
Power dissipation	75	mW
DC Forward Current	30	mA
Peak Forward Current [1]	160	mA
Reverse Voltage	5	V
Operating/Storage Temperature	-40°C To +85°C	
Lead Solder Temperature [2]	260°C For 3 Seconds	
Lead Solder Temperature [3]	260°C For 5 Seconds	

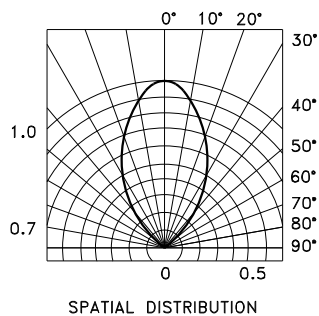
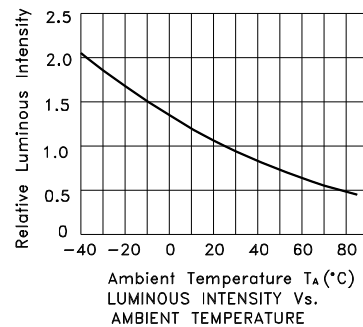
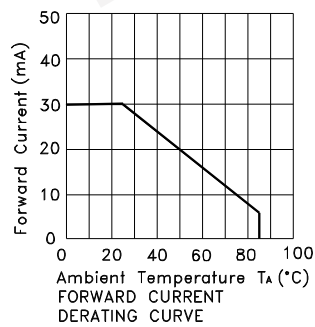
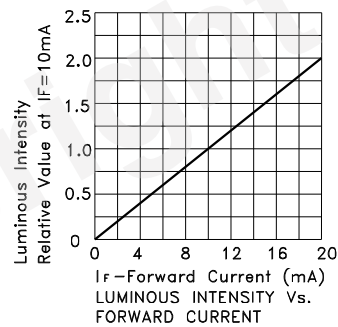
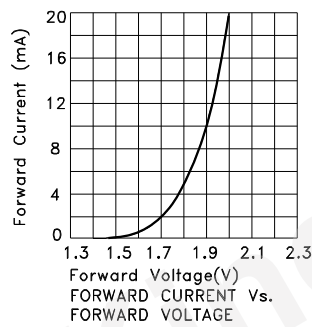
Notes:

1. 1/10 Duty Cycle, 0.1ms Pulse Width.
2. 2mm below package base.
3. 5mm below package base.



High Efficiency Red

L-1503ID



TL08xx JFET-Input Operational Amplifiers

1 Features

- Low Power Consumption: 1.4 mA/ch Typical
- Wide Common-Mode and Differential Voltage Ranges
- Low Input Bias Current: 30 pA Typical
- Low Input Offset Current: 5 pA Typical
- Output Short-Circuit Protection
- Low Total Harmonic Distortion: 0.003% Typical
- High Input Impedance: JFET Input Stage
- Latch-Up-Free Operation
- High Slew Rate: 13 V/μs Typical
- Common-Mode Input Voltage Range Includes V_{CC+}

2 Applications

- Tablets
- White goods
- Personal electronics
- Computers

3 Description

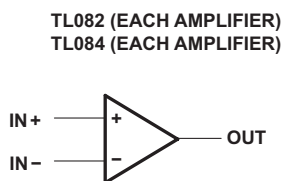
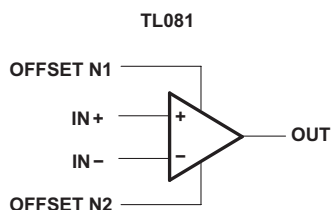
The TL08xx JFET-input operational amplifier family is designed to offer a wider selection than any previously developed operational amplifier family. Each of these JFET-input operational amplifiers incorporates well-matched, high-voltage JFET and bipolar transistors in a monolithic integrated circuit. The devices feature high slew rates, low input bias and offset currents, and low offset-voltage temperature coefficient.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
TL084xD	SOIC (14)	8.65 mm × 3.91 mm
TL08xxFK	LCCC (20)	8.89 mm × 8.89 mm
TL084xJ	CDIP (14)	19.56 mm × 6.92 mm
TL084xN	PDIP (14)	19.3 mm × 6.35 mm
TL084xNS	SO (14)	10.3 mm × 5.3 mm
TL084xPW	TSSOP (14)	5.0 mm × 4.4 mm

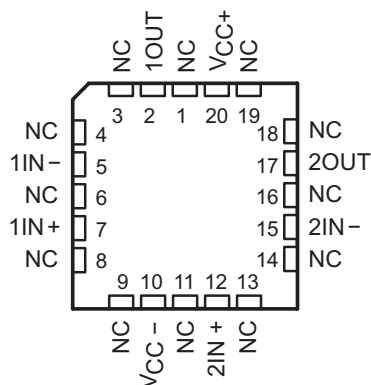
(1) For all available packages, see the orderable addendum at the end of the data sheet.

Schematic Symbol

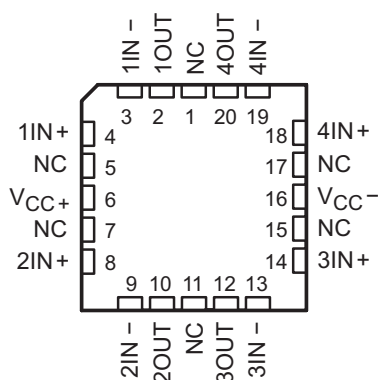


5 Pin Configuration and Functions

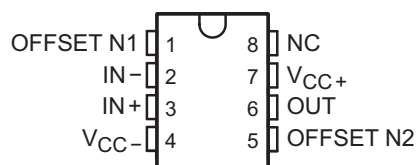
**TL082 FK Package
20-Pin LCCC
Top View**



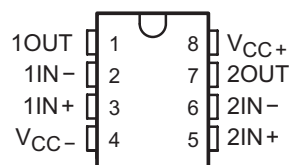
**TL084 FK Package
20-Pin LCCC
Top View**



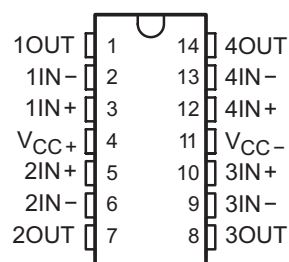
**TL081 and TL081x D, P, and PS Package
8-Pin SOIC, PDIP, and SO
Top View**



**TL082 and TL082x D, JG, P, PS and PW Package
8-Pin SOIC, CDIP, PDIP, SO, and TSSOP
Top View**



**TL084 and TL084x D, J, N, NS and PW Package
14-Pin SOIC, CDIP, PDIP, SO, and TSSOP
Top View**



Pin Functions

NAME	PIN					I/O	DESCRIPTION
	TL081 SOIC, PDIP, SO	TL082 SOIC, CDIP, PDIP, SO, TSSOP	TL082 LCCC	TL084 SOIC, CDIP, PDIP, SO, TSSOP	TL084 LCCC		
1IN-	—	2	5	2	3	I	Negative input
1IN+	—	3	7	3	4	I	Positive input
1OUT	—	1	2	1	2	O	Output
2IN-	—	6	15	6	9	I	Negative input
2IN+	—	5	12	5	8	I	Positive input
2OUT	—	7	17	7	10	O	Output
3IN-	—	—	—	9	13	I	Negative input
3IN+	—	—	—	10	14	I	Positive input
3OUT	—	—	—	8	12	O	Output
4IN-	—	—	—	13	19	I	Negative input
4IN+	—	—	—	12	18	I	Positive input
4OUT	—	—	—	14	20	O	Output

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

				MIN	MAX	UNIT
V _{CC+}	Supply voltage ⁽²⁾			18		V
V _{CC–}				–18		
V _{ID}	Differential input voltage ⁽³⁾			±30		V
V _I	Input voltage ⁽²⁾⁽⁴⁾			±15		V
Duration of output short circuit ⁽⁵⁾				Unlimited		
Continuous total power dissipation				See Dissipation Rating Table		
T _A	Operating free-air temperature		TL08_C TL08_AC TL08_BC	0	70	°C
			TL08_I	–40	85	
			TL084Q	–40	125	
			TL08_M	–55	125	
			Operating virtual junction temperature			
T _C	Case temperature for 60 seconds	FK package	TL08_M	260		°C
	Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	J or JG package	TL08_M	300		°C
T _{stg}	Storage temperature			–65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltage values, except differential voltages, are with respect to the midpoint between V_{CC+} and V_{CC-}.
- (3) Differential voltages are at IN₊, with respect to IN₋.
- (4) The magnitude of the input voltage must never exceed the magnitude of the supply voltage or 15 V, whichever is less.
- (5) The output may be shorted to ground or to either supply. Temperature and/or supply voltages must be limited to ensure that the dissipation rating is not exceeded.

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	1000	V
		Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	1500	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

				MIN	MAX	UNIT
V _{CC+}	Supply voltage			5	15	V
V _{CC-}	Supply voltage			–5	–15	V
V _{CM}	Common-mode voltage			V _{CC-} + 4	V _{CC+} – 4	V
T _A	Ambient temperature	TL08xM		–55	125	°C
		TL08xQ		–40	125	
		TL08xI		–40	85	
		TL08xC		0	70	

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		TL08xx								UNIT
		D (SOIC)		N (PDIP)	NS (SO)	P (PDIP)	PS (SO)	PW (TSSOP)		
		8 PINS	14 PINS	14 PINS	14 PINS	{PIN COUNT} PINS	{PIN COUNT} PINS	8 PINS	14 PINS	
R _{θJA}	Junction-to-ambient thermal resistance ⁽²⁾⁽³⁾	97	86	76	80	85	95	149	113	°C/W

- (1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report, [SPRA953](#).
- (2) Maximum power dissipation is a function of T_{J(max)}, R_{θJA}, and T_A. The maximum allowable power dissipation at any allowable ambient temperature is P_D = (T_{J(max)} – T_A) / R_{θJA}. Operating at the absolute maximum T_J of 150°C can affect reliability.
- (3) The package thermal impedance is calculated in accordance with JESD 51-7.

6.5 Electrical Characteristics for TL08xC, TL08xxC, and TL08xl

V_{CC±} = ±15 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _A ⁽¹⁾	TL081C, TL082C, TL084C			TL081AC, TL082AC, TL084AC			TL081BC, TL082BC, TL084BC			TL081I, TL082I, TL084I			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
V _{IO}	Input offset voltage	V _O = 0, R _S = 50 Ω	25°C	3		15	3		6	2		3	3		6	mV
			Full range	20			7.5			5			9			
α _{VIO}	Temperature coefficient of input offset voltage	V _O = 0, R _S = 50 Ω	Full range	18			18			18			18			μV/°C
I _{IO}	Input offset current ⁽²⁾	V _O = 0	25°C	5		200	5		100	5		100	5		100	pA
			Full range	2			2			2			10			nA
I _{IB}	Input bias current ⁽²⁾	V _O = 0	25°C	30		400	30		200	30		200	30		200	pA
			Full range	10			7			7			20			nA
V _{ICR}	Common-mode input voltage range		25°C	±11	−12 to 15		±11	−12 to 15		±11	−12 to 15		±11	−12 to 15	V	
V _{OM}	Maximum peak output voltage swing	R _L = 10 kΩ	25°C	±12	±13.5		±12	±13.5		±12	±13.5		±12	±13.5		V
		R _L ≥ 10 kΩ	Full range	±12		±12		±12		±12		±12				
		R _L ≥ 2 kΩ		±10	±12		±10	±12		±10	±12					
A _{VD}	Large-signal differential voltage amplification	V _O = ±10 V, R _L ≥ 2 kΩ	25°C	25	200		50	200		50	200		50	200		V/mV
			Full range	15		15		25		25						
B ₁	Unity-gain bandwidth		25°C	3			3			3			3			MHz
r _i	Input resistance		25°C	10 ¹²			10 ¹²			10 ¹²			10 ¹²			Ω
CMRR	Common-mode rejection ratio	V _{IC} = V _{ICR} min, V _O = 0, R _S = 50 Ω	25°C	70	86		75	86		75	86		75	86		dB
k _{SVR}	Supply-voltage rejection ratio (ΔV _{CC±} /ΔV _{IO})	V _{CC} = ±15 V to ±9 V, V _O = 0, R _S = 50 Ω	25°C	70	86		80	86		80	86		80	86		dB

- (1) All characteristics are measured under open-loop conditions with zero common-mode voltage, unless otherwise specified. Full range for T_A is 0°C to 70°C for TL08_C, TL08_AC, TL08_BC and –40°C to 85°C for TL08_I.
- (2) Input bias currents of an FET-input operational amplifier are normal junction reverse currents, which are temperature sensitive, as shown in [Figure 13](#). Pulse techniques must be used that maintain the junction temperature as close to the ambient temperature as possible.

Electrical Characteristics for TL08xC, TL08xxC, and TL08xl (continued)

 $V_{CC\pm} = \pm 15\text{ V}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS	$T_A^{(1)}$	TL081C, TL082C, TL084C			TL081AC, TL082AC, TL084AC			TL081BC, TL082BC, TL084BC			TL081I, TL082I, TL084I			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
I_{CC} Supply current (each amplifier)	$V_O = 0$, No load	25°C		1.4	2.8		1.4	2.8		1.4	2.8		1.4	2.8	mA
V_{O1}/V_{O2} Crosstalk attenuation	$A_{VD} = 100$	25°C		120			120			120			120		dB

6.6 Electrical Characteristics for TL08xM and TL084x

 $V_{CC\pm} = \pm 15\text{ V}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS ⁽¹⁾	T_A	TL081M, TL082M			TL084Q, TL084M			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	
V_{IO} Input offset voltage	$V_O = 0$, $R_S = 50\ \Omega$	25°C		3	6		3	9	mV
		Full range			9			15	
α_{VIO} Temperature coefficient of input offset voltage	$V_O = 0$, $R_S = 50\ \Omega$	Full range		18			18		$\mu\text{V}/^\circ\text{C}$
I_{IO} Input offset current ⁽²⁾	$V_O = 0$	25°C		5	100		5	100	pA
		125°C			20			20	nA
I_{IB} Input bias current ⁽²⁾	$V_O = 0$	25°C		30	200		30	200	pA
		125°C			50			50	nA
V_{ICR} Common-mode input voltage range		25°C	± 11	–12 to 15		± 11	–12 to 15		V
V_{OM} Maximum peak output voltage swing	$R_L = 10\text{ k}\Omega$	25°C	± 12	± 13.5		± 12	± 13.5		V
	$R_L \geq 10\text{ k}\Omega$	Full range	± 12			± 12			
	$R_L \geq 2\text{ k}\Omega$		± 10	± 12		± 10	± 12		
A_{VD} Large-signal differential voltage amplification	$V_O = \pm 10\text{ V}$, $R_L \geq 2\text{ k}\Omega$	25°C		25	200		25	200	V/mV
		Full range		15			15		
B_1 Unity-gain bandwidth		25°C		3			3		MHz
r_i Input resistance		25°C		10^{12}			10^{12}		Ω
CMRR Common-mode rejection ratio	$V_{IC} = V_{ICRmin}$, $V_O = 0$, $R_S = 50\ \Omega$	25°C	80	86		80	86		dB
k_{SVR} Supply-voltage rejection ratio ($\Delta V_{CC\pm}/\Delta V_{IO}$)	$V_{CC} = \pm 15\text{ V}$ to $\pm 9\text{ V}$, $V_O = 0$, $R_S = 50\ \Omega$	25°C	80	86		80	86		dB
I_{CC} Supply current (each amplifier)	$V_O = 0$, No load	25°C		1.4	2.8		1.4	2.8	mA
V_{O1}/V_{O2} Crosstalk attenuation	$A_{VD} = 100$	25°C		120			120		dB

(1) All characteristics are measured under open-loop conditions, with zero common-mode input voltage, unless otherwise specified.

(2) Input bias currents of a FET-input operational amplifier are normal junction reverse currents, which are temperature sensitive, as shown in Figure 13. Pulse techniques must be used that maintain the junction temperatures as close to the ambient temperature as possible.

6.7 Operating Characteristics

 $V_{CC\pm} = \pm 15\text{ V}$, $T_A = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
SR Slew rate at unity gain	$V_I = 10\text{ V}$, $R_L = 2\text{ k}\Omega$, $C_L = 100\text{ pF}$, See Figure 19	8 ⁽¹⁾	13		V/ μs
	$V_I = 10\text{ V}$, $R_L = 2\text{ k}\Omega$, $C_L = 100\text{ pF}$, $T_A = -55^\circ\text{C}$ to 125°C , See Figure 19	5 ⁽¹⁾			

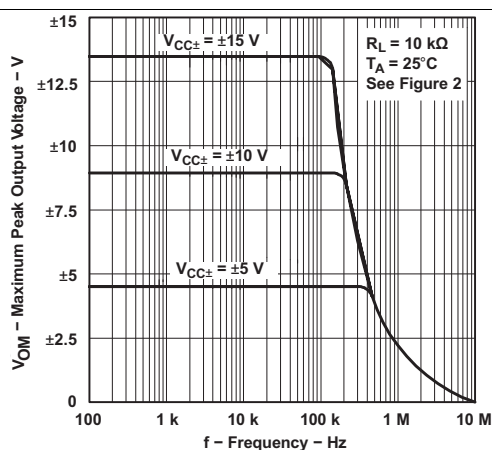
(1) On products compliant to MIL-PRF-38535, this parameter is not production tested.

6.9 Typical Characteristics

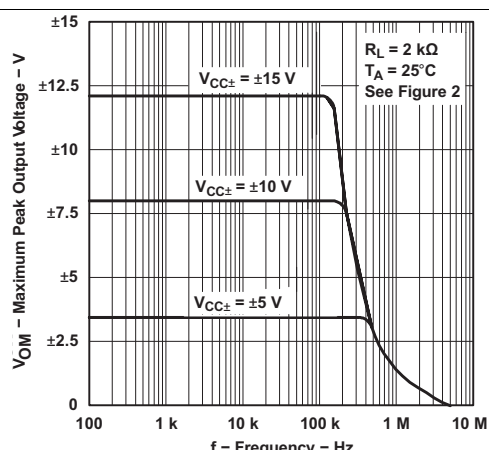
Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices. The Figure numbers referenced in the following graphs are located in [Parameter Measurement Information](#).

Table 1. Table of Graphs

			Figure
V_{OM}	Maximum peak output voltage	versus Frequency versus Free-air temperature versus Load resistance versus Supply voltage	Figure 1, Figure 2, Figure 3 Figure 4 Figure 5 Figure 6
A_{VD}	Large-signal differential voltage amplification	versus Free-air temperature versus Load resistance	Figure 7 Figure 8
	Differential voltage amplification	versus Frequency with feed-forward compensation	Figure 9
P_D	Total power dissipation	versus Free-air temperature	Figure 10
I_{CC}	Supply current	versus Free-air temperature versus Supply voltage	Figure 11 Figure 12
I_{IB}	Input bias current	versus Free-air temperature	Figure 13
	Large-signal pulse response	versus Time	Figure 14
V_O	Output voltage	versus Elapsed time	Figure 15
CMRR	Common-mode rejection ratio	versus Free-air temperature	Figure 16
V_n	Equivalent input noise voltage	versus Frequency	Figure 17
THD	Total harmonic distortion	versus Frequency	Figure 18



**Figure 1. Maximum Peak Output Voltage
vs
Frequency**



**Figure 2. Maximum Peak Output Voltage
vs
Frequency**

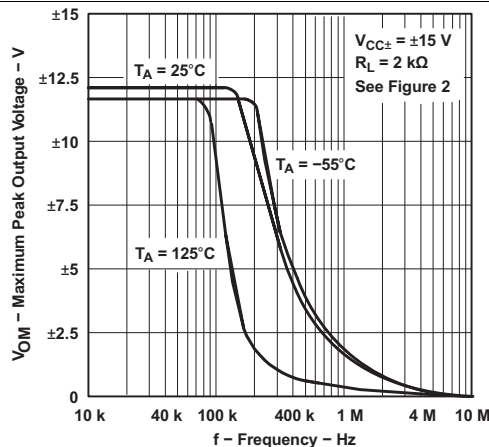


Figure 3. Maximum Peak Output Voltage
vs
Frequency

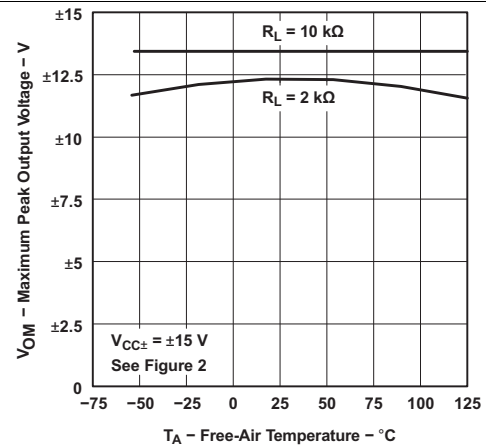


Figure 4. Maximum Peak Output Voltage
vs
Free-Air Temperature

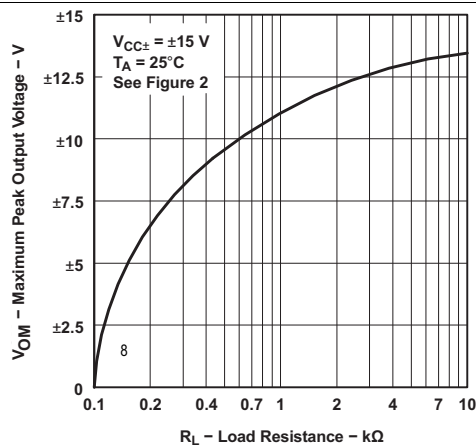


Figure 5. Maximum Peak Output Voltage
vs
Load Resistance

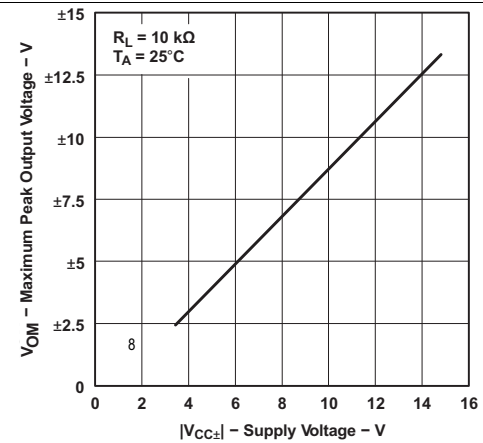


Figure 6. Maximum Peak Output Voltage
vs
Supply Voltage

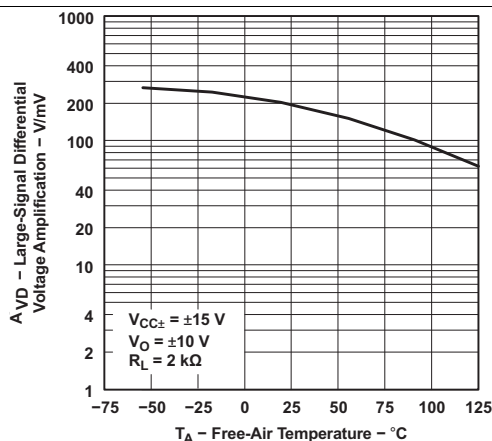


Figure 7. Large-Signal Differential Voltage Amplification
vs
Free-Air Temperature

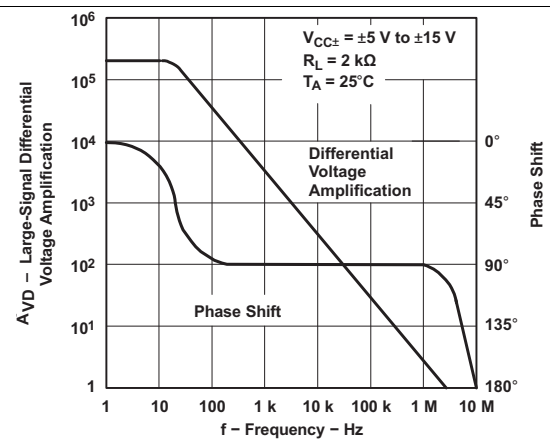
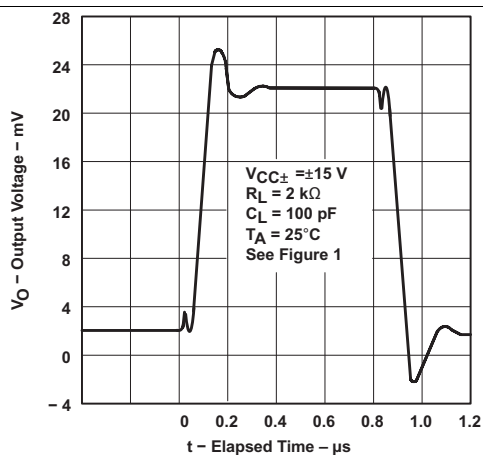
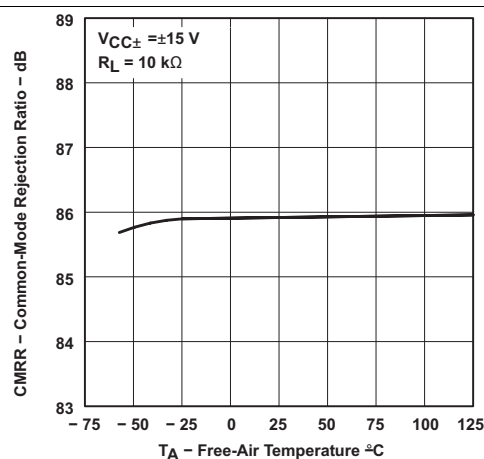


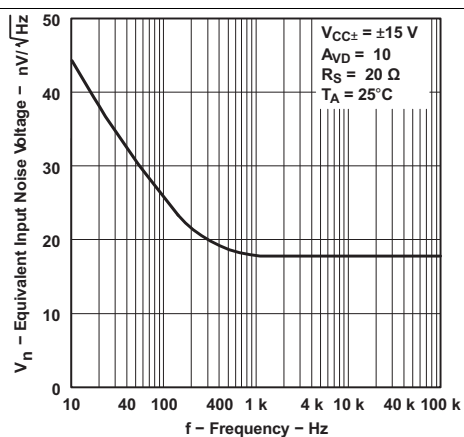
Figure 8. Large-Signal Differential Voltage Amplification and
Phase Shift
vs
Frequency



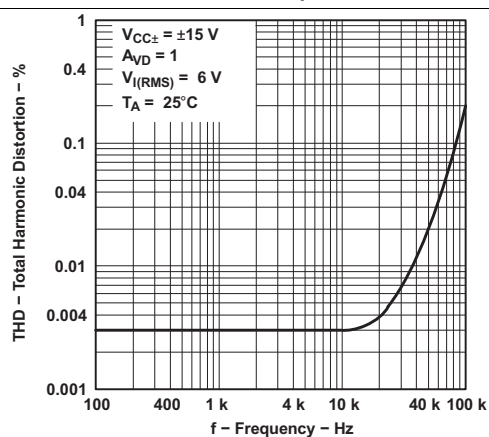
**Figure 15. Output Voltage
vs
Elapsed Time**



**Figure 16. Common-Mode Rejection Ratio
vs
Free-Air Temperature**



**Figure 17. Equivalent Input Noise Voltage
vs
Frequency**



**Figure 18. Total Harmonic Distortion
vs
Frequency**

7 Parameter Measurement Information

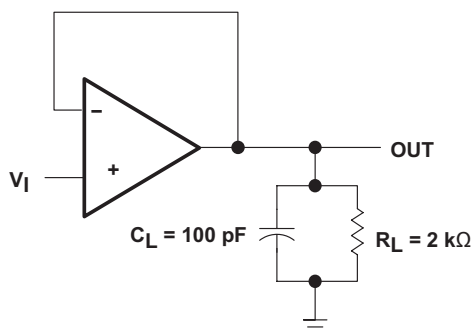


Figure 19. Test Figure 1

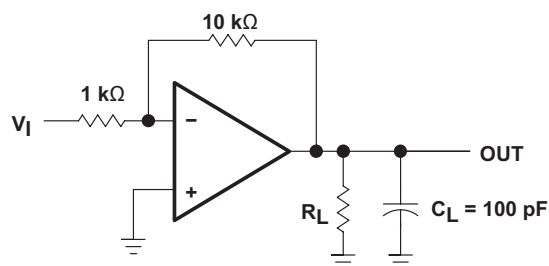


Figure 20. Test Figure 2

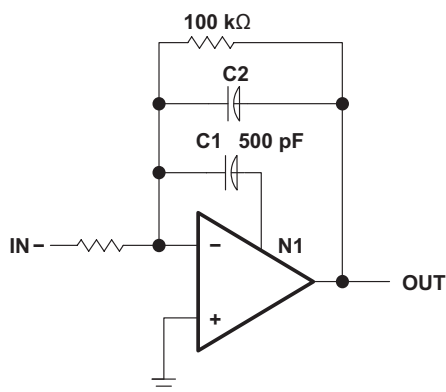


Figure 21. Test Figure 3

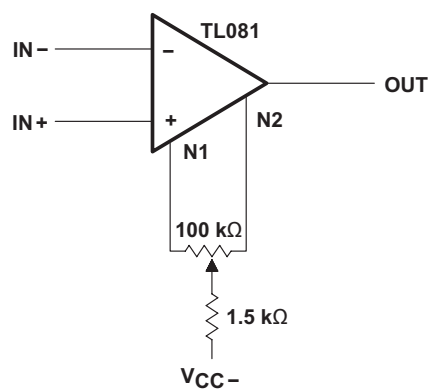


Figure 22. Test Figure 4